

Data sheet acquired from Harris Semiconductor SCHS228

CD74AC14, CD74ACT14

September 1998

Hex Inverting Schmitt Trigger

Features

- . Operates with Much Slower than Standard Input Rise and Fall Slew Rates
- Exceptionally High Noise Immunity
- Exceeds 2kV ESD Protection MIL-STD-883, Method
- SCR-Latchup-Resistant CMOS Process and Circuit
- Speed of Bipolar FAST™/AS/S with Significantly **Reduced Power Consumption**
- · Balanced Propagation Delays
- AC Types Feature 1.5V to 5.5V Operation and Balanced Noise Immunity at 30% of the Supply
- ±24mA Output Drive Current
 - Fanout to 15 FAST™ ICs
 - Drives 50Ω Transmission Lines
- · Greater Noise Immunity Than Standard Inverters

Description

The CD74AC14 and CD74ACT14 each contain six inverting Schmitt Triggers in one package. These devices use the Harris Advanced CMOS Logic technology.

Ordering Information

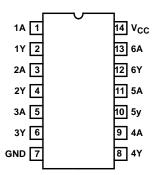
PART NUMBER	TEMP. RANGE (^O C)	PACKAGE	PKG. NO.	
CD74AC14	-55 to 125	14 Ld PDIP	E14.3	
CD74ACT14	-55 to 125	14 Ld PDIP	E14.3	
CD74AC14	-55 to 125	14 Ld SOIC	M14.15	
CD74ACT14	-55 to 125	14 Ld SOIC	M14.15	

NOTES:

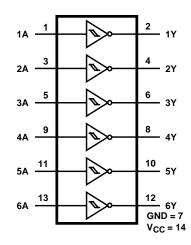
- 1. When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.
- 2. Wafer and die for this part number is available which meets all electrical specifications. Please contact your local sales office or Harris customer service for ordering information.

Pinout

CD74AC14, CD74ACT14 (PDIP, SOIC) **TOP VIEW**



Functional Diagram



TRUTH TABLE

INPUTS	OUTPUTS					
A	Y					
L	Н					
Н	L					

FIGURE 1. HYSTERESIS DEFINITION AND CHARACTERISTIC

CD74AC14, CD74ACT14

Absolute Maximum Ratings

DC Supply Voltage, V _{CC} 0.5V to 6V
DC Input Diode Current, I _{IK}
For $V_1 < -0.5V$ or $V_1 > V_{CC} + 0.5V$
DC Output Diode Current, IOK
For $V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$
DC Output Source or Sink Current per Output Pin, IO
For $V_O > -0.5V$ or $V_O < V_{CC} + 0.5V$
DC V _{CC} or Ground Current, I _{CC or} I _{GND} (Note 3) ±100mA

Thermal Information

	Thermal Resistance (Typical, Note 5)	θ _{JA} (°C/W)
	PDIP Package	90
	SOIC Package	175
	Maximum Junction Temperature (Plastic Package)	150 ^o C
ľ	Maximum Storage Temperature Range6	65°C to 150°C
ľ	Maximum Lead Temperature (Soldering 10s)	300°C

Operating Conditions

Temperature Range, T _A 55°C to 125°C
Supply Voltage Range, V _{CC} (Note 4)
AC Types1.5V to 5.5V
ACT Types
DC Input or Output Voltage, V _I , V _O 0V to V _{CC}
Input Rise and Fall Slew Rate, dt/dv (Note 6)
AC Types, 1.5V to 5.5V
ACT Types, 4.5V to 5.5V

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTES:

- 3. For up to 4 outputs per device, add $\pm 25 \text{mA}$ for each additional output.
- 4. Unless otherwise specified, all voltages are referenced to ground.
- 5. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.
- 6. 5 Outputs switching: V_{CC} = 5V; Load = 500 Ω , 50pF; T_A = Full Temperature Range For AC, V_I = 5.5V sawtooth; ACT, V_I = 3V sawtooth.

DC Electrical Specifications

			TEST CONDITIONS		25°C		-40°C TO 85°C		-55°C TO 125°C		
PARAMETER	SYMBOL	V _I (V)	I _O (mA)	V _{CC} (V)	MIN	MAX	MIN	MAX	MIN	MAX	UNITS
AC TYPES											
Positive-Going Threshold Voltage	V _T +	-	-	5	2.6	3.4	2.6	3.4	2.6	3.4	V
Negative-Going Threshold Voltage	V _T -	-	-	5	1.6	2.4	1.6	2.4	1.6	2.4	V
Hysteresis Voltage	V _H	-	-	5	0.5	-	0.5	-	0.5	-	V
High Level Output Voltage	V _{ОН}	V _T + or V _T -	-0.05	1.5	1.4	-	1.4	-	1.4	-	V
			-0.05	3	2.9	-	2.9	-	2.9	-	V
			-0.05	4.5	4.4	-	4.4	-	4.4	-	V
			-4	3	2.58	-	2.48	-	2.4	-	V
			-24	4.5	3.94	-	3.8	-	3.7	-	V
			-75 (Note 7, 8)	5.5	-	-	3.85	-	-	-	V
			-50 (Note 7, 8)	5.5	-	-	-	-	3.85	-	V

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DC Electrical Specifications (Continued)

			ST ITIONS	Vcc	25	oc.		C TO	-55°C TO 125°C		
PARAMETER	SYMBOL	V _I (V)	I _O (mA)	(V)	MIN	MAX	MIN	MAX	MIN	MAX	UNITS
Low Level Output Voltage	V _{OL}	V _T + or V _T -	0.05	1.5	-	0.1	-	0.1	-	0.1	V
			0.05	3	-	0.1	-	0.1	-	0.1	V
			0.05	4.5	-	0.1	-	0.1	-	0.1	V
			12	3	-	0.36	-	0.44	-	0.5	V
			24	4.5	-	0.36	-	0.44	-	0.5	V
			75 (Note 7, 8)	5.5	-	-	-	1.65	-	-	V
			50 (Note 7, 8)	5.5	-	-	-	-	-	1.65	V
Input Leakage Current	lį	V _{CC} or GND	-	5.5	-	±0.1	-	±1	-	±1	μА
Quiescent Supply Current, SSI	Icc	V _{CC} or GND	0	5.5	-	4	-	40	-	80	μА
ACT TYPES											
Positive-Going Threshold Voltage	V _T +	-	-	5	1.4	2	1.4	2	1.4	2	V
Negative-Going Threshold Voltage	V _T -	-	-	5	0.8	1.3	0.8	1.3	0.8	1.3	V
Hysteresis Voltage	V _H	-	-	5	0.4	-	0.4	-	0.4	-	V
High Level Output Voltage	V _{OH}	V _T + or V _T -	-0.05	4.5	4.4	-	4.4	-	4.4	-	V
			-24	4.5	3.94	-	3.8	-	3.7	-	V
			-75 (Note 7, 8)	5.5	-	-	3.85	-	-	-	V
			-50 (Note 7, 8)	5.5	-	-	-	-	3.85	-	V
Low Level Output Voltage	V _{OL}	V _T + or V _T -	0.05	4.5	-	0.1	-	0.1	-	0.1	V
			24	4.5	-	0.36	-	0.44	-	0.5	V
			75 (Note 7, 8)	5.5	-	-	-	1.65	-	-	V
			50 (Note 7, 8)	5.5	-	-	-	-	-	1.65	V
Input Leakage Current	lį	V _{CC} or GND	-	5.5	-	±0.1	-	±1	-	±1	μА
Quiescent Supply Current, SSI	Icc	V _{CC} or GND	0	5.5	-	4	-	40	-	80	μА
Additional Supply Current per Input Pin TTL Inputs High 1 Unit Load	Δl _{CC}	V _{CC} -2.1	-	4.5 to 5.5	-	2.4	-	2.8	-	3	mA

NOTES:

- 7. Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.
- 8. Test verifies a minimum 50Ω transmission-line-drive capability at 85° C, 75Ω at 125° C.

ACT Input Load Table

INPUT	UNIT LOAD					
All	0.21					

NOTE: Unit load is ΔI_{CC} limit specified in DC Electrical Specifications Table, e.g., 2.4mA max at 25°C.

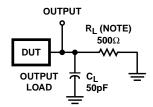
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$\textbf{Switching Specifications} \ \, \textbf{Input } t_f, \, t_f = 3 \text{ns}, \, C_L = 50 \text{pF (Worst Case)}$

			-40°	C TO 85°	5°C		-55°C TO 125°C		
PARAMETER	SYMBOL	V _{CC} (V)	MIN	TYP	MAX	MIN	TYP	MAX	UNITS
AC TYPES									
Propagation Delay, Input to Output	^t PLH [,] ^t PHL	5 (Note 10)	2.7	-	9.5	2.6	-	10.5	ns
Input Capacitance	Cl	-	-	-	10	-	-	10	pF
Power Dissipation Capacitance	C _{PD} (Note 11)	-	-	45	-	-	45	-	pF
ACT TYPES								•	•
Propagation Delay, Input to	t _{PLH}	5	3.7	-	13.2	3.6	-	14.5	ns
Output	t _{PHL}	(Note 10)	2.4	-	8.6	2.4	-	9.5	
Input Capacitance	Cl	-	-	-	10	-	-	10	pF
Power Dissipation Capacitance	C _{PD} (Note 11)	-	-	45	-	-	45	-	pF

NOTES:

- 9. Limits tested at 100%.
- 10. 5V Min at 5.5V, Max at 4.5V.
- 11. C_{PD} is used to determine the dynamic power consumption per gate. AC: $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$ ACT: $P_D = V_{CC}^2 f_i (C_{PD} + C_L) + V_{CC} \Delta I_{CC}$ where f_i = input frequency, C_L = output load capacitance, V_{CC} = supply voltage.



NOTE: For AC Series Only: When $\rm V_{CC}$ = 1.5V, $\rm R_{L}$ = 1k $\Omega.$

	CD74AC	CD74ACT
Input Level	V _{CC}	3V
Input Switching Voltage, V _S	0.5 V _{CC}	1.5V
Output Switching Voltage, V _S	0.5 V _{CC}	0.5 V _{CC}

FIGURE 2. PROPAGATION DELAY TIMES

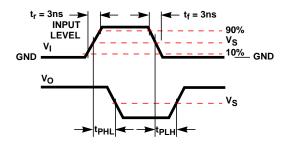


FIGURE 3.

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